

FCC ID: 2AYSS-20V6

Portable device

According to §15.247(e)(i) and §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission's guidelines.

According to KDB447498 D01 General RF Exposure Guidance V06

The 1-g SAR and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances \leq 50 mm are determined by:

$[(\text{max. power of channel, including tune-up tolerance, mW}) / (\text{min. test separation distance, mm})] \cdot [\sqrt{f(\text{GHz})}] \leq 3.0 \text{ for 1-g SAR and } \leq 7.5 \text{ for 10-g extremity SAR, where:}$

- $f(\text{GHz})$ is the RF channel transmit frequency in GHz
- Power and distance are rounded to the nearest mW and mm before calculation
- The result is rounded to one decimal place for comparison

When the minimum test separation distance is $<$ 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.

BT:

Modulation	Channel Freq. (GHz)	Conducted power (dBm)	Conducted power (mW)	Tune-up power (dBm)	Max tune-up power (dBm)	Max tune-up power (mW)	Distance (mm)	Result calculation	SAR Exclusion threshold	SAR test exclusion
GFSK	2.402	-5.274	0.30	-5±1	-4	0.40	<5	0.12340	3.00	YES
	2.44	-4.302	0.37	-5±1	-4	0.40	<5	0.12437	3.00	YES
	2.480	-4.946	0.32	-5±1	-4	0.40	<5	0.12539	3.00	YES
$\pi/4$ -DQPSK	2.402	-4.68	0.34	-4±1	-3	0.50	<5	0.15535	3.00	YES
	2.44	-3.65	0.43	-4±1	-3	0.50	<5	0.15658	3.00	YES
	2.480	-4.243	0.38	-4±1	-3	0.50	<5	0.15785	3.00	YES
8-DPSK	2.402	-4.22	0.38	-4±1	-3	0.50	<5	0.15535	3.00	YES
	2.44	-3.257	0.47	-4±1	-3	0.50	<5	0.15658	3.00	YES
	2.480	-3.798	0.42	-4±1	-3	0.50	<5	0.15785	3.00	YES
GFSK - BLE	2.402	-8.312	0.15	-8±1	-7	0.20	<5	0.06185	3.00	YES
	2.44	-8.618	0.14	-8±1	-7	0.20	<5	0.06233	3.00	YES
	2.480	-7.975	0.16	-8±1	-7	0.20	<5	0.06284	3.00	YES

Conclusion:

For the max result : 0.15785W/Kg \leq 3.0 for 1g SAR, No SAR is required.



Signature:

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